

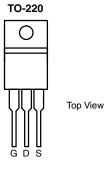
IRLB4030PBF-VB Datasheet N-Channel 100 V (D-S) MOSFET

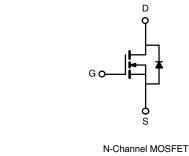
PRODUCT SUMMARY				
V _{DS} (V)	100			
$R_{DS(on)} (\Omega)$ at $V_{GS} = 10 V$	0.0030			
I _D (A) ^a	180			
Configuration	Single			

FEATURES

- Trench Power MOSFET
- Package with Low Thermal Resistance
- AEC-Q101 Qualified^d
- + 100 % $\rm R_g$ and UIS Tested







ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \degree C$, unless otherwise noted)					
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	100	V	
Gate-Source Voltage		V _{GS}	± 20	V	
Continuous Drain Current	$T_C = 25 \ ^{\circ}C^a$	1	180		
Continuous Drain Current	T _C = 125 °C	I _D	140		
Continuous Source Current (Diode Conduction) ^a		I _S	180	А	
Pulsed Drain Current ^b		I _{DM}	480		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	73		
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	266	mJ	
Maximum Power Dissipation ^b	T _C = 25 °C	P	250	W	
	T _C = 125 °C	PD	83	٧V	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	°C	

THERMAL RESISTANCE RATINGS				
PARAMETER		SYMBOL	LIMIT	UNIT
Junction-to-Ambient	PCB Mount ^c	R _{thJA}	40	°C/W
Junction-to-Case (Drain)		R _{thJC}	0.6	0/10

Notes

a. Base on Tc = 25°C.

b. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$

c. When mounted on 1" square PCB (FR-4 material).

d. Parametric verification ongoing.

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static	•	1			<u> </u>			
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0, I_D = 250 \ \mu A$		100	-	-	v	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$		3.0	3.5	v	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$		-	-	± 100	nA	
		$V_{GS} = 0 V$	V _{DS} = 100 V	-	-	1		
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	V _{DS} = 100 V, T _J = 125 °C	-	-	50	μA	
		$V_{GS} = 0 V$	V _{DS} = 100 V, T _J = 175 °C	-	-	500		
On-State Drain Current ^a	I _{D(on)}	$V_{GS} = 10 V$	$V_{DS} \ge 5 V$	120	-	-	Α	
		V _{GS} = 10 V	I _D = 20 A	-	0.0030	-		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V	I _D = 20 A, T _J = 125 °C	-	0.0064	-	Ω	
		V _{GS} = 10 V	I _D = 20 A, T _J = 175 °C	-	0.0080	-		
Forward Transconductanceb	9 _{fs}	V _{DS} = 15 V, I _D = 20 A		-	82	-	S	
Dynamic ^b		•						
Input Capacitance	C _{iss}			-	5780	7230		
Output Capacitance	C _{oss}	$V_{GS} = 0 V$	V V _{DS} = 25 V, f = 1 MHz	-	3070	3840	pF	
Reverse Transfer Capacitance	C _{rss}	-		-	305	385		
Total Gate Charge ^c	Qg			-	125	190		
Gate-Source Charge ^c	Q _{gs}	V _{GS} = 10 V	$V_{DS} = 50 \text{ V}, I_D = 70 \text{ A}$	-	28	-	nC	
Gate-Drain Charge ^c	Q _{gd}	-		-	46	-		
Gate Resistance	R _g	f = 1 MHz		1.6	3.3	5	Ω	
Turn-On Delay Time ^c	t _{d(on)}	$\begin{array}{l} V_{\text{DD}} = 50 \text{ V}, R_{\text{L}} = 0.7 \ \Omega \\ I_{\text{D}} \cong 70 \text{ A}, V_{\text{GEN}} = 10 \text{ V}, R_{\text{g}} = 1 \ \Omega \end{array}$		-	16	25		
Rise Time ^c	t _r			-	110	165	ns	
Turn-Off Delay Time ^c	t _{d(off)}			-	40	60		
Fall Time ^c	t _f			-	12	20		
Source-Drain Diode Ratings and Char	acteristics ^b							
Pulsed Current ^a	I _{SM}			-	-	480	Α	
Forward Voltage	V _{SD}	$I_{\rm F} = 100 \rm A, V_{\rm GS} = 0$		-	0.9	1.5	V	

Notes

a. Pulse test; pulse width $\leq 300~\mu\text{s},$ duty cycle $\leq 2~\%.$

b. Guaranteed by design, not subject to production testing.

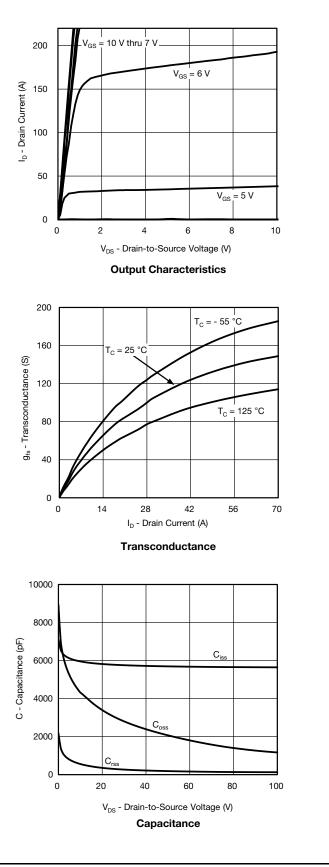
c. Independent of operating temperature.

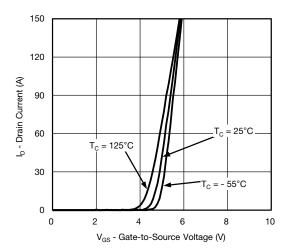
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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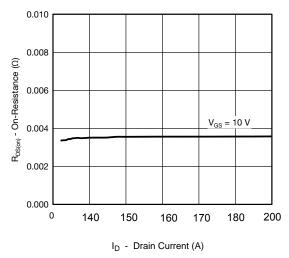


TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)

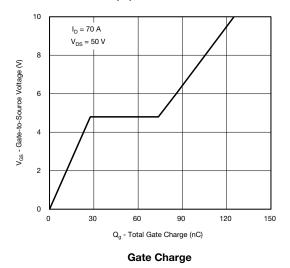




Transfer Characteristics

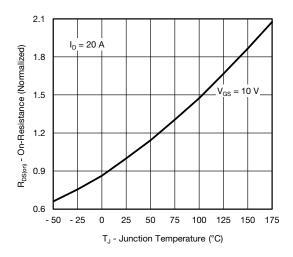


R_{DS(on)} vs. Drain Current

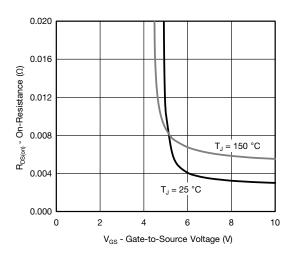




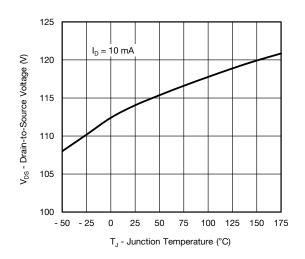
TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)



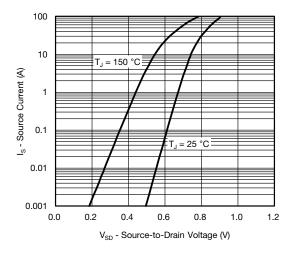
On-Resistance vs. Junction Temperature



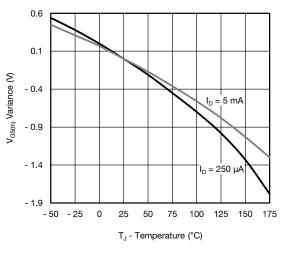
On-Resistance vs. Gate-to-Source Voltage



Drain Source Breakdown vs. Junction Temperature



Source Drain Diode Forward Voltage

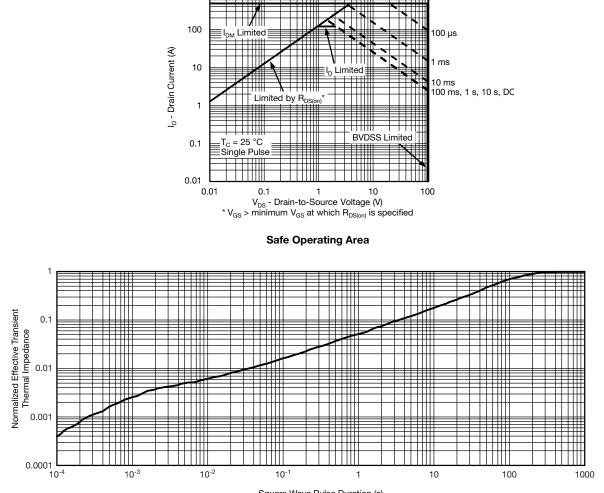


Threshold Voltage



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)

1000

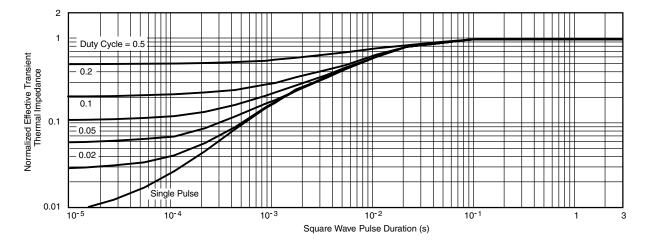


Square Wave Pulse Duration (s)

Normalized Thermal Transient Impedance, Junction-to-Ambient



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case

Note

• The characteristics shown in the two graphs

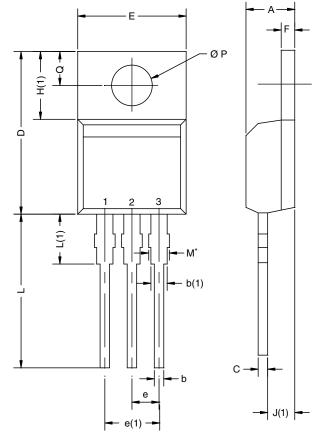
- Normalized Transient Thermal Impedance Junction to Ambient (25 °C)

- Normalized Transient Thermal Impedance Junction to Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.



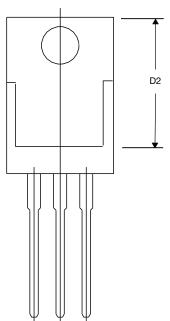
TO-220AB



	MILLIMETERS		INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
D2	12.19	12.70	0.480	0.500	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: T14-0413-Rev. P, 16-Jun-14 DWG: 5471					

Note

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM





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